

<b>Notice of References Cited</b>		Application/Control No. 09/842,948	Applicant(s)/Patent Under Reexamination PETRY ET AL.	
		Examiner PHILIP WANG	Art Unit 2191	Page 1 of 1

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*	Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	B US-6,813,621	11-2004	Taylor et al.	707/102
C	US-			
D	US-			
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J	US-			
K	US-			
L	US-			
M	US-			

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\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)  
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.